

**Search Notes**

Application/Control No.

10/575,446

Examiner

/Yonel Beaulieu/

Applicant(s)/Patent under  
Reexamination

TAKAMATSU ET AL.

Art Unit

3661

**SEARCHED**

Class	Subclass	Date	Examiner
701	51	3/21/2009	YB
	56		
	90		
477	34		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
Int. Search		3/21/2009	YB

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
WEST+Int.+Fwd/Bwd	3/21/2009	YB